

<b>Form PTO 1449A</b>  <b>U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>  Information Disclosure Statement by Applicant	<b>ATTY. DOCKET NUMBER:</b> 78384 (18-32 US DIV1)	<b>SERIAL NUMBER:</b> 10/706,142
	<b>APPLICANT:</b> PHILLIPS ET AL	
	<b>FILING DATE:</b> 11/12/2003	<b>GROUP:</b> 1732

## U.S. Patent Documents

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING APPEAL
		3,338,730	Aug 29, 1967	Slade et al.	428	142	
		4,168,983	Sep 25, 1979	Vittands et al.	106	14.12	
		4,310,584	Jan 12, 1982	Cooper et al	428	212	
		4,705,356	Nov 10, 1987	Berning et al.	350	166	
		4,838,648	Jun 13, 1989	Phillips et al	350	166	
		4,930,866	Jun 5, 1990	Berning et al	350	320	
		5,059,245	Oct 22, 1991	Phillips et al	106	22	
		5,084,351	Jan 28, 1992	Phillips et al.	428	411.1	
		5,135,812	Aug 4, 1992	Phillips et al.	428	403	
		5,171,363	Dec 15, 1992	Phillips et al.	106	31.65	
		5,278,590	Jan 11, 1994	Phillips et al	359	589	
		5,437,931	Aug 1, 1995	Tsai et al.	428	446	
		5,447,335	Sept 5, 1995	Haslop	283	91	
		5,571,624	Nov 5, 1996	Phillips et al.	428	403	
		5,700,550	Dec 23, 1997	Uyama et al	428	212	
		5,907,436	May 25, 1999	Perry et al	359	576	

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant*

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## Foreign Patent Documents

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
		488652	Nov 18, 1977	AU	B44F	1/12		
		1696245	Jan 13, 1972	DE	D21H	5/10		No
		3932505	Apr 11, 1991	DE	B44F	1/12		No
		19611383	Sep 25, 1997	DE	B44F	1/12		No
		19731968	Jan 28, 1999	DE	B44F	1/12		No
		19744953	Apr 15, 1999	DE	B44F	1/12		No
		19639165	Oct 16, 2003	DE	C09B	67/02		No
		0138194	Oct 11, 1984	EP	B32B	27/08		
		0185396	Dec 20, 1985	EP	D21H	5/10		No
		0420261	Apr 3, 1991	EP	G06K	19/00		No
		0660262	Jan 28, 1995	EP	G06K	19/16		
		0170439	Apr 5, 1995	EP	G02B	5/20		
		0914261	May 12, 1999	EP	B42D	15/10		
		0395410	Aug 13, 1997	EP	G02B	5/20		
		0756945	Feb 5, 1997	EP	B42D	15/00		
		0698256	Oct 22, 1997	EP	G06K	19/14		

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	No
		0741370	May 19, 1998	EP	G06K	19/18		No
		1719636	Nov 8, 2006	EP	B42D	15/10		
		11010771	Jan 19, 1999	JP	B32B	7/02	Abstract only	
		93/23251	Nov 25, 1993	WO	B41M	3/14		
		95/17475	Jan 29, 1995	WO	C09C	1/00		
		97/19820	Jun 5, 1997	WO	B42D	15/10		

## Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)

		"Optical Thin-Film Security Devices", J.A. Dobrowolski, Optical Security Document, Rudolf Van Renesse, Artech House, 1998, pgs. 289-328
		"Paper Based Document Security – a Review" Rudolf L. van Renesse, European Conference on Security and Detection, April 28-30, 1997, Conference Publication No, 437, pg. 75-80
		"Diffractive Microstructures for Security Applications: M. T. Gale, Paul Scherrer Institute, Zurich, IEEE Conference Publication London 1991, Pgs 205-209, Sept. 16-18, 1991
		"Research on thin film anticounterfeiting coatings at the National Research Council of Canada", J. A. Dobrowolski et al., Applied Optics, Vol. 28, No. 14, July 15, 1989, Pgs. 2702-2717
		Definition of "directly" from Webster's Third New International Dictionary, 1993, pg. 641
EXAMINER	/Mathieu Vargot/	DATE CONSIDERED 03/21/2008
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